

10688072_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10688072 on June 16, 2004

Original Classifications

5 250/396R
4 250/492.21
3 250/287
3 250/288
3 250/309
3 250/423R
3 250/427
2 250/398
2 250/492.2
2 315/111.81

Cross-Reference Classifications

9 250/423R
6 250/492.2
4 250/287
4 250/397
4 250/398
3 313/359.1
3 313/363.1
3 315/111.41
3 315/111.81
2 250/281
2 250/288
2 250/307
2 250/310
2 250/396R
2 250/427
2 313/231.31
2 313/362.1
2 315/111.31
2 445/50

Combined Classifications

12 250/423R
8 250/492.2
7 250/287
7 250/396R
6 250/398
5 250/288
5 250/397
5 250/427
5 315/111.81
4 250/492.21

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4 313/359.1
3 250/281
3 250/309
3 313/362.1
3 313/363.1
3 315/111.41
2 216/41
2 250/282
2 250/307
2 250/310
2 250/492.3
2 313/231.31
2 315/111.31
2 347/123
2 445/50

10688072_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10688072 on June 16, 2004

| | | |
|----|-------------|--|
| 12 | 250/423R | (3 OR, 9 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/423R | ION GENERATION |
| 8 | 250/492.2 | (2 OR, 6 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/492.1 | IRRADIATION OF OBJECTS OR MATERIAL |
| | 250/492.2 | .Irradiation of semiconductor devices |
| 7 | 250/287 | (3 OR, 4 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/281 | IONIC SEPARATION OR ANALYSIS |
| | 250/286 | .Ion beam pulsing means with detector synchronizing means |
| | 250/287 | ..With time-of-flight indicator |
| 7 | 250/396R | (5 OR, 2 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/396R | WITH CHARGED PARTICLE BEAM DEFLECTION OR FOCUSSING |
| 6 | 250/398 | (2 OR, 4 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/396R | WITH CHARGED PARTICLE BEAM DEFLECTION OR FOCUSSING |
| | 250/398 | .With target means |
| 5 | 250/288 | (3 OR, 2 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/281 | IONIC SEPARATION OR ANALYSIS |
| | 250/288 | .With sample supply means |
| 5 | 250/397 | (1 OR, 4 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/396R | WITH CHARGED PARTICLE BEAM DEFLECTION OR FOCUSSING |
| | 250/397 | .With detector |
| 5 | 250/427 | (3 OR, 2 XR) |
| | Class 250 : | RADIANT ENERGY |
| | 250/423R | ION GENERATION |
| | 250/427 | .Electron bombardment type |

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- 5 315/111.81 (2 OR, 3 XR)
Class 315 : ELECTRIC LAMP AND DISCHARGE DEVICES: SYSTEMS

315/111.01 DISCHARGE DEVICE LOAD WITH FLUENT MATERIAL
SUPPLY TO THE DISCHARGE SPACE
315/111.81 .Electron or ion source
- 4 250/492.21 (4 OR, 0 XR)
Class 250 : RADIANT ENERGY
250/492.1 IRRADIATION OF OBJECTS OR MATERIAL
250/492.2 .Irradiation of semiconductor devices
250/492.21 ..Ion bombardment
- 4 313/359.1 (1 OR, 3 XR)
Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES
313/359.1 WITH POSITIVE OR NEGATIVE ION ACCELERATION
- 3 250/281 (1 OR, 2 XR)
Class 250 : RADIANT ENERGY
250/281 IONIC SEPARATION OR ANALYSIS
- 3 250/309 (3 OR, 0 XR)
Class 250 : RADIANT ENERGY
250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED
PARTICLES
250/309 .Positive ion probe or microscope type
- 3 313/362.1 (1 OR, 2 XR)
Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES
313/359.1 WITH POSITIVE OR NEGATIVE ION ACCELERATION
313/362.1 .Supplying ionizable material (e.g., gas or
vapor)
- 3 313/363.1 (0 OR, 3 XR)
Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES
313/359.1 WITH POSITIVE OR NEGATIVE ION ACCELERATION
313/363.1 .Extraction or target electrode
- 3 315/111.41 (0 OR, 3 XR)
Class 315 : ELECTRIC LAMP AND DISCHARGE DEVICES: SYSTEMS

315/111.01 DISCHARGE DEVICE LOAD WITH FLUENT MATERIAL
SUPPLY TO THE DISCHARGE SPACE
315/111.21 .Plasma generating
315/111.41 ..With magnetic field
- 2 216/41 (1 OR, 1 XR)
Class 216 : ETCHING A SUBSTRATE: PROCESSES

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216/41 10688072_CLSTITLES
MASKING OF A SUBSTRATE USING MATERIAL RESISTAN
TO AN ETCHANT (I.E., ETCH RESIST)

2 250/282 (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/281 IONIC SEPARATION OR ANALYSIS
250/282 .Methods

2 250/307 (0 OR, 2 XR)
Class 250 : RADIANT ENERGY
250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED
PARTICLES
250/307 .Methods

2 250/310 (0 OR, 2 XR)
Class 250 : RADIANT ENERGY
250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED
PARTICLES
250/310 .Electron probe type

2 250/492.3 (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/492.1 IRRADIATION OF OBJECTS OR MATERIAL
250/492.3 .Ion or electron beam irradiation

2 313/231.31 (0 OR, 2 XR)
Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES
313/231.01 FLUENT MATERIAL SUPPLY OR FLOW DIRECTING MEANS
313/231.31 .Plasma

2 315/111.31 (0 OR, 2 XR)
Class 315 : ELECTRIC LAMP AND DISCHARGE DEVICES: SYSTEMS
315/111.01 DISCHARGE DEVICE LOAD WITH FLUENT MATERIAL
SUPPLY TO THE DISCHARGE SPACE
315/111.21 .Plasma generating
315/111.31 ..With extraction electrode

2 347/123 (1 OR, 1 XR)
Class 347 : INCREMENTAL PRINTING OF SYMBOLIC INFORMATION
347/111 ELECTRIC MARKING APPARATUS OR PROCESSES
347/112 .Electrostatic
347/120 ..By information carrying flow of invisible
charged particles
347/123 ...Specific ionographic head

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2 445/50 (0 OR, 2 XR)
Class 445 : ELECTRIC LAMP OR SPACE DISCHARGE COMPONENT OR
DEVICE MANUFACTURING
445/1 PROCESS
445/46 .Electrode making
445/49 ..Electrode shaping
445/50 ...Emissive type